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Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	2 Core, 32-Bit
Speed	1.067GHz
Co-Processors/DSP	Signal Processing; SPE, Security; SEC
RAM Controllers	DDR2, DDR3
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.5V, 1.8V, 2.5V, 3.3V
Operating Temperature	-40°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	1023-BBGA, FCBGA
Supplier Device Package	1023-FCPBGA (33x33)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8572ecvjarle

2.1.2 Recommended Operating Conditions

Table 2 provides the recommended operating conditions for this device. Note that the values shown are the recommended and tested operating conditions. Proper device operation outside these conditions is not guaranteed.

Table 2. Recommended Operating Conditions

Characteristic		Symbol	Recommended Value	Unit	Notes
Core supply voltage		V_{DD}	$1.1\text{ V} \pm 55\text{ mV}$	V	—
PLL supply voltage		AV_{DD}	$1.1\text{ V} \pm 55\text{ mV}$	V	1
Core power supply for SerDes transceivers		SV_{DD}	$1.1\text{ V} \pm 55\text{ mV}$	V	—
Pad power supply for SerDes transceivers		XV_{DD}	$1.1\text{ V} \pm 55\text{ mV}$	V	—
DDR SDRAM Controller I/O supply voltage	DDR2 SDRAM Interface	GV_{DD}	$1.8\text{ V} \pm 90\text{ mV}$	V	—
	DDR3 SDRAM Interface		$1.5\text{ V} \pm 75\text{ mV}$		—
Three-speed Ethernet I/O voltage		LV_{DD}	$3.3\text{ V} \pm 165\text{ mV}$ $2.5\text{ V} \pm 125\text{ mV}$	V	4
		TV_{DD}	$3.3\text{ V} \pm 165\text{ mV}$ $2.5\text{ V} \pm 125\text{ mV}$		4
DUART, system control and power management, I ² C, and JTAG I/O voltage		OV_{DD}	$3.3\text{ V} \pm 165\text{ mV}$	V	3
Local bus and GPIO I/O voltage		BV_{DD}	$3.3\text{ V} \pm 165\text{ mV}$ $2.5\text{ V} \pm 125\text{ mV}$ $1.8\text{ V} \pm 90\text{ mV}$	V	—
Input voltage	DDR2 and DDR3 SDRAM Interface signals	MV_{IN}	GND to GV_{DD}	V	2
	DDR2 and DDR3 SDRAM Interface reference	MV_{REF}^n	$GV_{DD}/2 \pm 1\%$	V	—
	Three-speed Ethernet signals	LV_{IN} TV_{IN}	GND to LV_{DD} GND to TV_{DD}	V	4
	Local bus and GPIO signals	BV_{IN}	GND to BV_{DD}	V	—
	Local bus, DUART, SYSCLK, Serial RapidIO, system control and power management, I ² C, and JTAG signals	OV_{IN}	GND to OV_{DD}	V	3
Junction temperature range		T_J	0 to 105	°C	—

Notes:

1. This voltage is the input to the filter discussed in [Section 21.2.1, “PLL Power Supply Filtering,”](#) and not necessarily the voltage at the AV_{DD} pin, that may be reduced from V_{DD} by the filter.
2. **Caution:** MV_{IN} must not exceed GV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
3. **Caution:** OV_{IN} must not exceed OV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
4. **Caution:** LV_{IN} must not exceed LV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.

2.1.3 Output Driver Characteristics

Table 3 provides information on the characteristics of the output driver strengths.

Table 3. Output Drive Capability

Driver Type	Programmable Output Impedance (Ω)	Supply Voltage	Notes
Local bus interface utilities signals	25 35	$BV_{DD} = 3.3\text{ V}$ $BV_{DD} = 2.5\text{ V}$	1
	45(default) 45(default) 125	$BV_{DD} = 3.3\text{ V}$ $BV_{DD} = 2.5\text{ V}$ $BV_{DD} = 1.8\text{ V}$	
DDR2 signal	18 36 (half strength mode)	$GV_{DD} = 1.8\text{ V}$	2
DDR3 signal	20 40 (half strength mode)	$GV_{DD} = 1.5\text{ V}$	2
eTSEC/10/100 signals	45	$L/TV_{DD} = 2.5/3.3\text{ V}$	—
DUART, system control, JTAG	45	$OV_{DD} = 3.3\text{ V}$	—
I2C	150	$OV_{DD} = 3.3\text{ V}$	—

Notes:

1. The drive strength of the local bus interface is determined by the configuration of the appropriate bits in PORIMPSR.
2. The drive strength of the DDR2 or DDR3 interface in half-strength mode is at $T_j = 105^\circ\text{C}$ and at GV_{DD} (min).

2.2 Power Sequencing

The MPC8572E requires its power rails to be applied in a specific sequence to ensure proper device operation. These requirements are as follows for power up:

1. V_{DD} , AV_{DD-n} , BV_{DD} , LV_{DD} , OV_{DD} , SV_{DD_SRDS1} and SV_{DD_SRDS2} , TV_{DD} , XV_{DD_SRDS1} and XV_{DD_SRDS2}
2. GV_{DD}

All supplies must be at their stable values within 50 ms.

Items on the same line have no ordering requirement with respect to one another. Items on separate lines must be ordered sequentially such that voltage rails on a previous step must reach 90% of their value before the voltage rails on the current step reach 10% of theirs.

To guarantee MCKE low during power-on reset, the above sequencing for GV_{DD} is required. If there is no concern about any of the DDR signals being in an indeterminate state during power-on reset, then the sequencing for GV_{DD} is not required.

Table 17. DDR2 and DDR3 SDRAM Interface Input AC Timing Specifications

At recommended operating conditions with GV_{DD} of 1.8 V \pm 5% for DDR2 or 1.5 V \pm 5% for DDR3.

Parameter	Symbol	Min	Max	Unit	Notes
Controller Skew for MDQS—MDQ/MECC	t_{CISKEW}	—	—	ps	1, 2
800 MHz	—	–200	200	—	—
667 MHz	—	–240	240	—	—
533 MHz	—	–300	300	—	—
400 MHz	—	–365	365	—	—

Note:

1. t_{CISKEW} represents the total amount of skew consumed by the controller between MDQS[n] and any corresponding bit that is captured with MDQS[n]. This should be subtracted from the total timing budget.
2. The amount of skew that can be tolerated from MDQS to a corresponding MDQ signal is called t_{DISKEW} . This can be determined by the following equation: $t_{DISKEW} = \pm(T/4 - \text{abs}(t_{CISKEW}))$ where T is the clock period and $\text{abs}(t_{CISKEW})$ is the absolute value of t_{CISKEW} .

Figure 3 shows the DDR2 and DDR3 SDRAM interface input timing diagram.

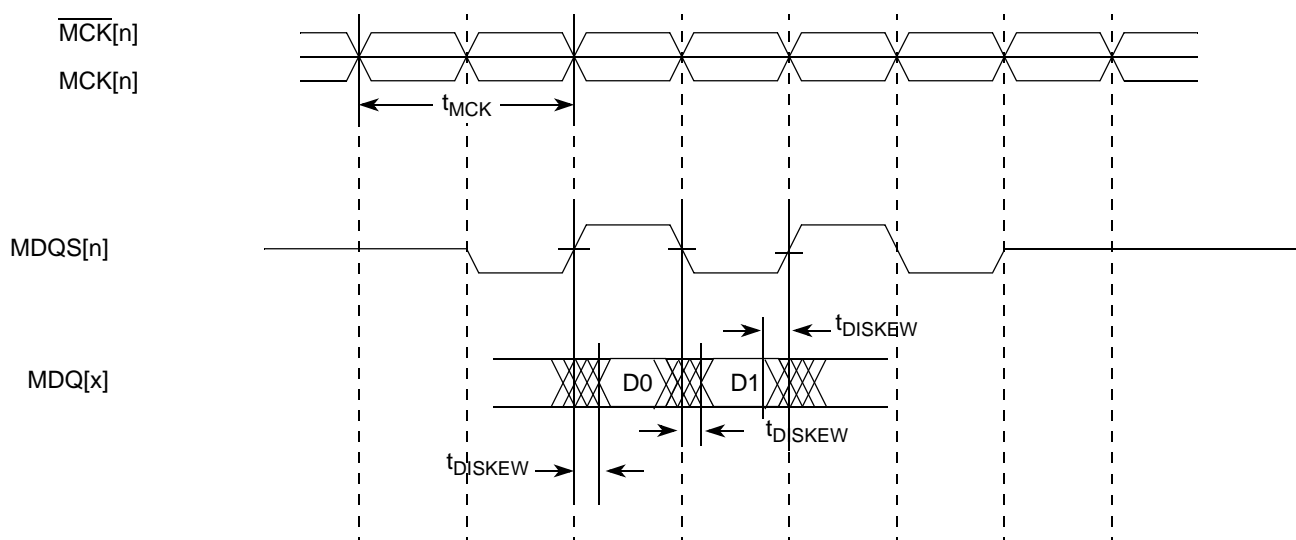


Figure 3. DDR2 and DDR3 SDRAM Interface Input Timing Diagram

6.2.2 DDR2 and DDR3 SDRAM Interface Output AC Timing Specifications

Table 18 contains the output AC timing targets for the DDR2 and DDR3 SDRAM interface.

Table 18. DDR2 and DDR3 SDRAM Interface Output AC Timing Specifications

At recommended operating conditions with GV_{DD} of 1.8 V \pm 5% for DDR2 or 1.5 V \pm 5% for DDR3.

Parameter	Symbol ¹	Min	Max	Unit	Notes
MCK[n] cycle time	t_{MCK}	2.5	5	ns	2
ADDR/CMD output setup with respect to MCK	t_{DDKHAS}			ns	3

Table 20 provides the differential specifications for the MPC8572E differential signals MDQS/ $\overline{\text{MDQS}}$ and MCK/ $\overline{\text{MCK}}$ when in DDR3 mode.

Table 20. DDR3 SDRAM Differential Electrical Characteristics

Parameter/Condition	Symbol	Min	Max	Unit	Notes
DC Input Signal Voltage	V_{IN}	—	—	mV	—
DC Differential Input Voltage	V_{ID}	—	—	mV	—
AC Differential Input Voltage	V_{IDAC}	—	—	mV	—
DC Differential Output Voltage	V_{OH}	—	—	mV	—
AC Differential Output Voltage	V_{OHAC}	—	—	mV	—
AC Differential Cross-point Voltage	V_{IXAC}	—	—	mV	—
Input Midpoint Voltage	V_{MP}	—	—	mV	—

7 DUART

This section describes the DC and AC electrical specifications for the DUART interface of the MPC8572E.

7.1 DUART DC Electrical Characteristics

Table 21 provides the DC electrical characteristics for the DUART interface.

Table 21. DUART DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
Supply voltage (3.3 V)	OV_{DD}	3.13	3.47	V
High-level input voltage	V_{IH}	2	$OV_{\text{DD}} + 0.3$	V
Low-level input voltage	V_{IL}	−0.3	0.8	V
Input current ($V_{\text{IN}}^1 = 0 \text{ V}$ or $V_{\text{IN}} = V_{\text{DD}}$)	I_{IN}	—	±5	μA
High-level output voltage ($OV_{\text{DD}} = \text{min}$, $I_{\text{OH}} = -2 \text{ mA}$)	V_{OH}	2.4	—	V
Low-level output voltage ($OV_{\text{DD}} = \text{min}$, $I_{\text{OL}} = 2 \text{ mA}$)	V_{OL}	—	0.4	V

Note:

1. The symbol V_{IN} , in this case, represents the OV_{IN} symbol referenced in Table 1.

The Fast Ethernet Controller (FEC) operates in MII mode only, and complies with the AC and DC electrical characteristics specified in this chapter for MII. Note that if FEC is used, eTSEC 3 and 4 are only available in SGMII mode.

8.1.1 eTSEC DC Electrical Characteristics

All MII, GMII, RMII, and TBI drivers and receivers comply with the DC parametric attributes specified in [Table 23](#) and [Table 24](#). All RGMII, RTBI and FIFO drivers and receivers comply with the DC parametric attributes specified in [Table 24](#). The RGMII and RTBI signals are based on a 2.5-V CMOS interface voltage as defined by JEDEC EIA/JESD8-5.

Table 23. GMII, MII, RMII, and TBI DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit	Notes
Supply voltage 3.3 V	LV_{DD} TV_{DD}	3.13	3.47	V	1, 2
Output high voltage ($LV_{DD}/TV_{DD} = \text{Min}$, $IOH = -4.0 \text{ mA}$)	VOH	2.40	$LV_{DD}/TV_{DD} + 0.3$	V	—
Output low voltage ($LV_{DD}/TV_{DD} = \text{Min}$, $IOL = 4.0 \text{ mA}$)	VOL	GND	0.50	V	—
Input high voltage	V_{IH}	2.0	$LV_{DD}/TV_{DD} + 0.3$	V	—
Input low voltage	V_{IL}	-0.3	0.90	V	—
Input high current ($V_{IN} = LV_{DD}$, $V_{IN} = TV_{DD}$)	I_{IH}	—	40	μA	1, 2,3
Input low current ($V_{IN} = \text{GND}$)	I_{IL}	-600	—	μA	3

Notes:

¹ LV_{DD} supports eTSECs 1 and 2.

² TV_{DD} supports eTSECs 3 and 4 or FEC.

³ The symbol V_{IN} , in this case, represents the LV_{IN} and TV_{IN} symbols referenced in [Table 1](#).

Table 24. MII, GMII, RMII, RGMII, TBI, RTBI, and FIFO DC Electrical Characteristics

Parameters	Symbol	Min	Max	Unit	Notes
Supply voltage 2.5 V	LV_{DD}/TV_{DD}	2.37	2.63	V	1,2
Output high voltage ($LV_{DD}/TV_{DD} = \text{Min}$, $IOH = -1.0 \text{ mA}$)	VOH	2.00	$LV_{DD}/TV_{DD} + 0.3$	V	—
Output low voltage ($LV_{DD}/TV_{DD} = \text{Min}$, $IOL = 1.0 \text{ mA}$)	VOL	GND - 0.3	0.40	V	—
Input high voltage	V_{IH}	1.70	$LV_{DD}/TV_{DD} + 0.3$	V	—
Input low voltage	V_{IL}	-0.3	0.70	V	—

Table 25. FIFO Mode Transmit AC Timing Specification (continued)

At recommended operating conditions with V_{DD}/TV_{DD} of $2.5V \pm 5\%$

Parameter/Condition	Symbol	Min	Typ	Max	Unit
TX_CLK, GTX_CLK peak-to-peak jitter	t_{FITJ}	—	—	250	ps
Rise time TX_CLK (20%–80%)	t_{FITR}	—	—	0.75	ns
Fall time TX_CLK (80%–20%)	t_{FITF}	—	—	0.75	ns
FIFO data TXD[7:0], TX_ER, TX_EN setup time to GTX_CLK	t_{FITDV}	2.0	—	—	ns
GTX_CLK to FIFO data TXD[7:0], TX_ER, TX_EN hold time	t_{FITDX}	0.5	—	3.0	ns

Notes:

1. The minimum cycle period (or maximum frequency) of the TX_CLK is dependent on the maximum platform frequency of the speed bins the part belongs to as well as the FIFO mode under operation. Refer to [Section 4.5, “Platform to eTSEC FIFO Restrictions,”](#) for more detailed description.

Table 26. FIFO Mode Receive AC Timing Specification

At recommended operating conditions with V_{DD}/TV_{DD} of $2.5V \pm 5\%$

Parameter/Condition	Symbol	Min	Typ	Max	Unit
RX_CLK clock period ¹	t_{FIR}	5.3	8.0	100	ns
RX_CLK duty cycle	t_{FIRH}/t_{FIR}	45	50	55	%
RX_CLK peak-to-peak jitter	t_{FIRJ}	—	—	250	ps
Rise time RX_CLK (20%–80%)	t_{FIRR}	—	—	0.75	ns
Fall time RX_CLK (80%–20%)	t_{FIRF}	—	—	0.75	ns
RXD[7:0], RX_DV, RX_ER setup time to RX_CLK	t_{FIRDV}	1.5	—	—	ns
RXD[7:0], RX_DV, RX_ER hold time to RX_CLK	t_{FIRDx}	0.5	—	—	ns

1. The minimum cycle period (or maximum frequency) of the RX_CLK is dependent on the maximum platform frequency of the speed bins the part belongs to as well as the FIFO mode under operation. Refer to [Section 4.5, “Platform to eTSEC FIFO Restrictions,”](#) for more detailed description.

Figure 7 and Figure 8 show the FIFO timing diagrams.

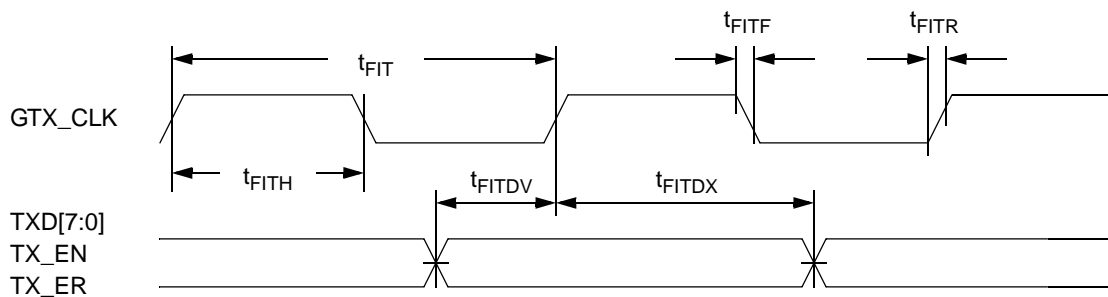

Figure 7. FIFO Transmit AC Timing Diagram

Figure 11 shows the GMII receive AC timing diagram.

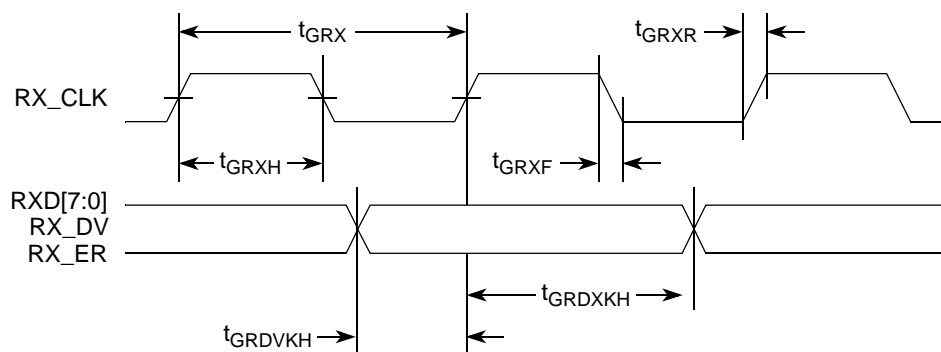


Figure 11. GMII Receive AC Timing Diagram

8.2.3 MII AC Timing Specifications

This section describes the MII transmit and receive AC timing specifications.

8.2.3.1 MII Transmit AC Timing Specifications

Table 29 provides the MII transmit AC timing specifications.

Table 29. MII Transmit AC Timing Specifications

At recommended operating conditions with V_{DD}/V_{DD} of 2.5/ 3.3 V \pm 5%.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
TX_CLK clock period 10 Mbps	t_{MTX}^2	—	400	—	ns
TX_CLK clock period 100 Mbps	t_{MTX}	—	40	—	ns
TX_CLK duty cycle	t_{MTXH}/t_{MTX}	35	—	65	%
TX_CLK to MII data TXD[3:0], TX_ER, TX_EN delay	t_{MTKHDx}	1	5	15	ns
TX_CLK data clock rise (20%-80%)	t_{MTXR}^2	1.0	—	4.0	ns
TX_CLK data clock fall (80%-20%)	t_{MTXF}^2	1.0	—	4.0	ns

Notes:

- The symbols used for timing specifications herein follow the pattern of $t_{(first\ two\ letters\ of\ functional\ block)(signal)(state)\ (reference)(state)}$ for inputs and $t_{(first\ two\ letters\ of\ functional\ block)(reference)(state)(signal)(state)}$ for outputs. For example, t_{MTKHDx} symbolizes MII transmit timing (MT) for the time t_{MTX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{MTX} represents the MII(M) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
- Guaranteed by design.

Figure 15 shows the TBI transmit AC timing diagram.

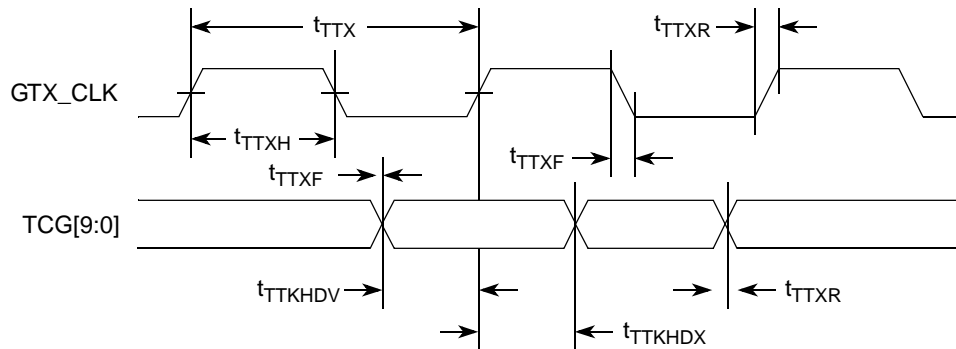


Figure 15. TBI Transmit AC Timing Diagram

8.2.4.2 TBI Receive AC Timing Specifications

Table 32 provides the TBI receive AC timing specifications.

Table 32. TBI Receive AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 2.5/ 3.3 V \pm 5%.

Parameter/Condition ³	Symbol ¹	Min	Typ	Max	Unit
Clock period for TBI Receive Clock 0, 1	t_{TRX}	—	16.0	—	ns
Skew for TBI Receive Clock 0, 1	t_{SKTRX}	7.5	—	8.5	ns
Duty cycle for TBI Receive Clock 0, 1	t_{TRXH}/t_{TRX}	40	—	60	%
RCG[9:0] setup time to rising edge of TBI Receive Clock 0, 1	t_{TRDVKH}	2.5	—	—	ns
RCG[9:0] hold time to rising edge of TBI Receive Clock 0, 1	t_{TRDXKH}	1.5	—	—	ns
Clock rise time (20%-80%) for TBI Receive Clock 0, 1	t_{TRXR}^2	0.7	—	2.4	ns
Clock fall time (80%-20%) for TBI Receive Clock 0, 1	t_{TRXF}^2	0.7	—	2.4	ns

Notes:

- The symbols used for timing specifications herein follow the pattern of $t_{(first\ two\ letters\ of\ functional\ block)(signal)(state)\ (reference)(state)}$ for inputs and $t_{(first\ two\ letters\ of\ functional\ block)(reference)(state)(signal)(state)}$ for outputs. For example, t_{TRDVKH} symbolizes TBI receive timing (TR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{TRX} clock reference (K) going to the high (H) state or setup time. Also, t_{TRDXKH} symbolizes TBI receive timing (TR) with respect to the time data input signals (D) went invalid (X) relative to the t_{TRX} clock reference (K) going to the high (H) state. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{TRX} represents the TBI (T) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall). For symbols representing skews, the subscript is skew (SK) followed by the clock that is being skewed (TRX).
- Guaranteed by design.
- The signals "TBI Receive Clock 0" and "TBI Receive Clock 1" refer to TSECn_RX_CLK and TSECn_TX_CLK pins respectively. These two clock signals are also referred as PMA_RX_CLK[0:1].

Table 48 provides the DC electrical characteristics for the local bus interface operating at $BV_{DD} = 1.8 \text{ V}$ DC.

Table 48. Local Bus DC Electrical Characteristics (1.8 V DC)

Parameter	Symbol	Min	Max	Unit
Supply voltage 1.8V	BV_{DD}	1.71	1.89	V
High-level input voltage	V_{IH}	$0.65 \times BV_{DD}$	$BV_{DD} + 0.3$	V
Low-level input voltage	V_{IL}	-0.3	$0.35 \times BV_{DD}$	V
Input current ($BV_{IN}^1 = 0 \text{ V}$ or $BV_{IN} = BV_{DD}$)	I_{IN}	TBD	TBD	μA
High-level output voltage ($I_{OH} = -100 \mu\text{A}$)	V_{OH}	$BV_{DD} - 0.2$	—	V
High-level output voltage ($I_{OH} = -2 \text{ mA}$)	V_{OH}	$BV_{DD} - 0.45$	—	V
Low-level output voltage ($I_{OL} = 100 \mu\text{A}$)	V_{OL}	—	0.2	V
Low-level output voltage ($I_{OL} = 2 \text{ mA}$)	V_{OL}	—	0.45	V

Note:

1. The symbol BV_{IN} , in this case, represents the BV_{IN} symbol referenced in Table 1.

10.2 Local Bus AC Electrical Specifications

Table 49 describes the general timing parameters of the local bus interface at $BV_{DD} = 3.3 \text{ V}$ DC.

Table 49. Local Bus General Timing Parameters ($BV_{DD} = 3.3 \text{ V}$ DC)—PLL Enabled

At recommended operating conditions with BV_{DD} of $3.3 \text{ V} \pm 5\%$.

Parameter	Symbol ¹	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	6.67	12	ns	2
Local bus duty cycle	t_{LBKH}/t_{LBK}	43	57	%	—
LCLK[n] skew to LCLK[m] or LSYNC_OUT	$t_{LBKSKEW}$	—	150	ps	7,8
Input setup to local bus clock (except $\overline{LGTA}/LUPWAIT$)	$t_{LBIVKH1}$	1.8	—	ns	3, 4
$\overline{LGTA}/LUPWAIT$ input setup to local bus clock	$t_{LBIVKH2}$	1.7	—	ns	3, 4
Input hold from local bus clock (except $\overline{LGTA}/LUPWAIT$)	$t_{LBIXKH1}$	1.0	—	ns	3, 4
$\overline{LGTA}/LUPWAIT$ input hold from local bus clock	$t_{LBIXKH2}$	1.0	—	ns	3, 4
LALE output negation to high impedance for LAD/LDP (LATCH hold time)	t_{LBOTOT}	1.5	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKHOV1}$	—	2.3	ns	—
Local bus clock to data valid for LAD/LDP	$t_{LBKHOV2}$	—	2.4	ns	3
Local bus clock to address valid for LAD	$t_{LBKHOV3}$	—	2.3	ns	3

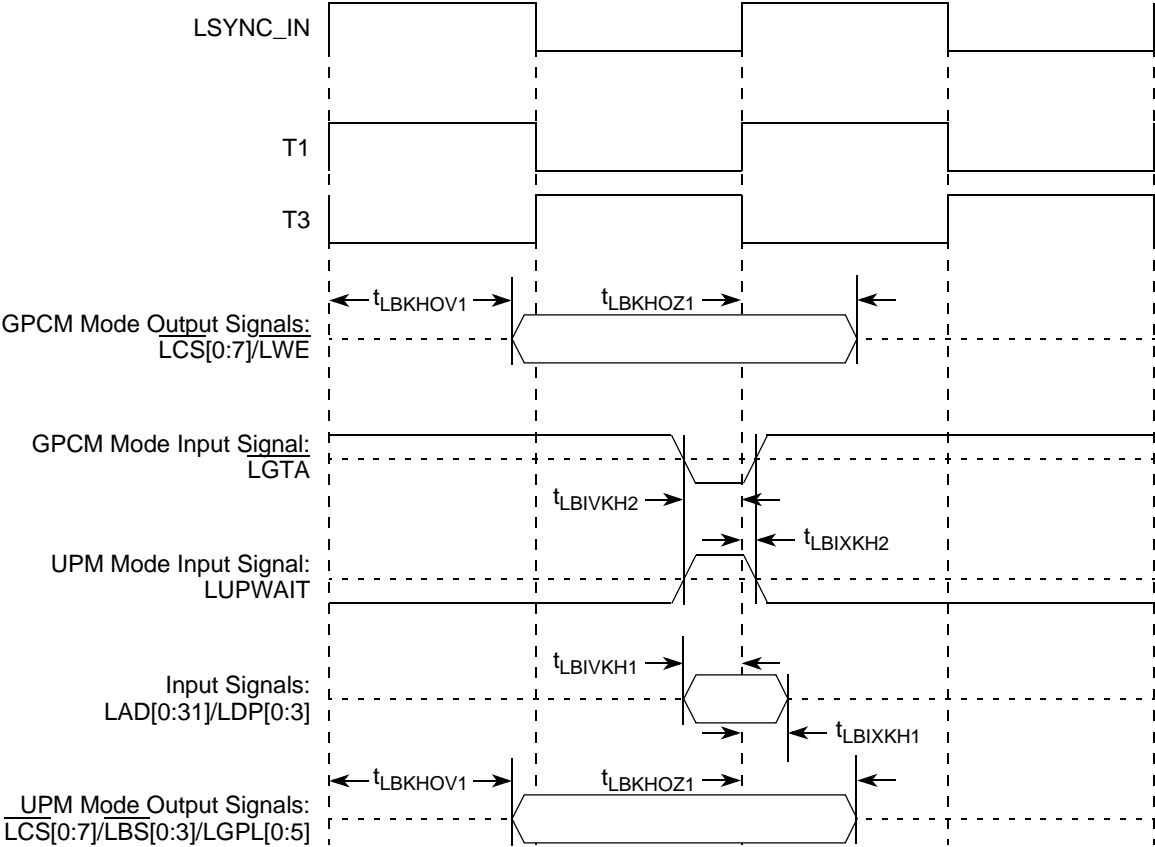


Figure 32. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 4 (PLL Enabled)

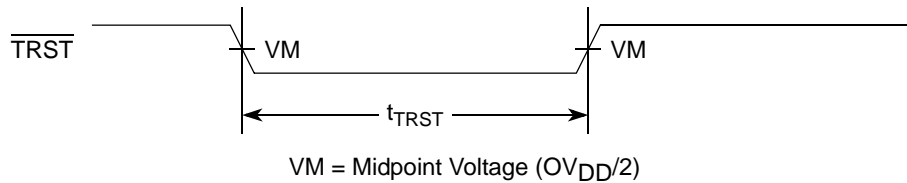


Figure 38. TRST Timing Diagram

Figure 39 provides the boundary-scan timing diagram.

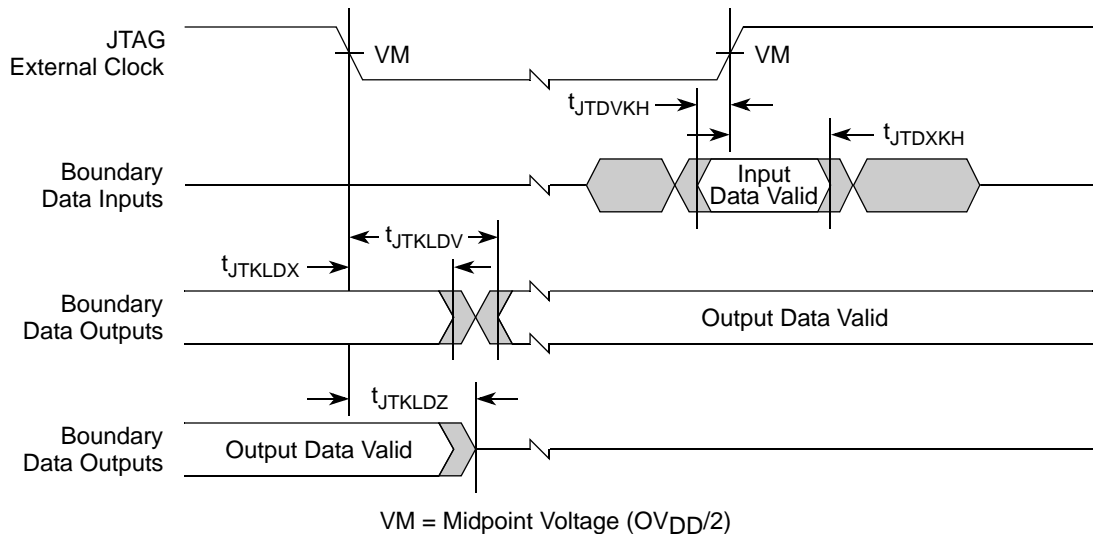


Figure 39. Boundary-Scan Timing Diagram

13 I²C

This section describes the DC and AC electrical characteristics for the I²C interfaces of the MPC8572E.

13.1 I²C DC Electrical Characteristics

Table 54 provides the DC electrical characteristics for the I²C interfaces.

Table 54. I²C DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit	Notes
Input high voltage level	V_{IH}	$0.7 \times OV_{DD}$	$OV_{DD} + 0.3$	V	—
Input low voltage level	V_{IL}	-0.3	$0.3 \times OV_{DD}$	V	—
Low level output voltage	V_{OL}	0	0.4	V	1
Pulse width of spikes which must be suppressed by the input filter	t_{I2KHKL}	0	50	ns	2
Input current each I/O pin (input voltage is between $0.1 \times OV_{DD}$ and $0.9 \times OV_{DD}(\text{max})$)	I_I	-10	10	μA	3

Table 54. I²C DC Electrical Characteristics (continued)

Capacitance for each I/O pin	C _I	—	10	pF	—
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Notes:

1. Output voltage (open drain or open collector) condition = 3 mA sink current.
2. Refer to the *MPC8572E PowerQUICC™ III Integrated Host Processor Family Reference Manual* for information on the digital filter used.
3. I/O pins will obstruct the SDA and SCL lines if OV_{DD} is switched off.

13.2 I²C AC Electrical Specifications

Table 55 provides the AC timing parameters for the I²C interfaces.

Table 55. I²C AC Electrical Specifications

At recommended operating conditions with OV_{DD} of 3.3 V ± 5%. All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 2).

Parameter	Symbol ¹	Min	Max	Unit
SCL clock frequency	f _{I2C}	0	400	kHz ⁴
Low period of the SCL clock	t _{I2CL}	1.3	—	μs
High period of the SCL clock	t _{I2CH}	0.6	—	μs
Setup time for a repeated START condition	t _{I2SVKH}	0.6	—	μs
Hold time (repeated) START condition (after this period, the first clock pulse is generated)	t _{I2SXKL}	0.6	—	μs
Data setup time	t _{I2DVKH}	100	—	ns
Data input hold time: CBUS compatible masters I ² C bus devices	t _{I2DXKL}	— 0 ²	— —	μs
Data output delay time	t _{I2OVKL}	—	0.9 ³	μs
Setup time for STOP condition	t _{I2PVKH}	0.6	—	μs
Bus free time between a STOP and START condition	t _{I2KHDX}	1.3	—	μs
Noise margin at the LOW level for each connected device (including hysteresis)	V _{NL}	0.1 × OV _{DD}	—	V
Noise margin at the HIGH level for each connected device (including hysteresis)	V _{NH}	0.2 × OV _{DD}	—	V

Table 55. I²C AC Electrical Specifications (continued)

At recommended operating conditions with OV_{DD} of 3.3 V ± 5%. All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 2).

Parameter	Symbol ¹	Min	Max	Unit
Capacitive load for each bus line	Cb	—	400	pF

Notes:

1. The symbols used for timing specifications herein follow the pattern t_{(first two letters of functional block)(signal)(state)(reference)(state)} for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{I2DVKH} symbolizes I²C timing (I2) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. Also, t_{I2SXKL} symbolizes I²C timing (I2) for the time that the data with respect to the START condition (S) went invalid (X) relative to the t_{I2C} clock reference (K) going to the low (L) state or hold time. Also, t_{I2PVKH} symbolizes I²C timing (I2) for the time that the data with respect to the STOP condition (P) reaching the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time.
2. As a transmitter, the MPC8572E provides a delay time of at least 300 ns for the SDA signal (referred to the VIHmin of the SCL signal) to bridge the undefined region of the falling edge of SCL to avoid unintended generation of START or STOP condition. When the MPC8572E acts as the I2C bus master while transmitting, the MPC8572E drives both SCL and SDA. As long as the load on SCL and SDA are balanced, the MPC8572E would not cause unintended generation of START or STOP condition. Therefore, the 300 ns SDA output delay time is not a concern. If, under some rare condition, the 300 ns SDA output delay time is required for the MPC8572E as transmitter, application note AN2919 referred to in note 4 below is recommended.
3. The maximum t_{I2OVKL} has only to be met if the device does not stretch the LOW period (t_{I2CL}) of the SCL signal.
4. The requirements for I²C frequency calculation must be followed. Refer to Freescale application note AN2919, *Determining the I²C Frequency Divider Ratio for SCL*.

Figure 40 provides the AC test load for the I²C.

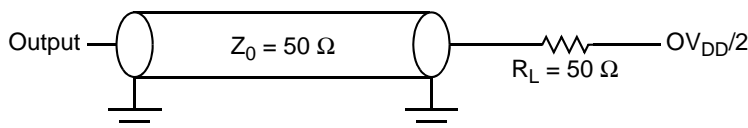
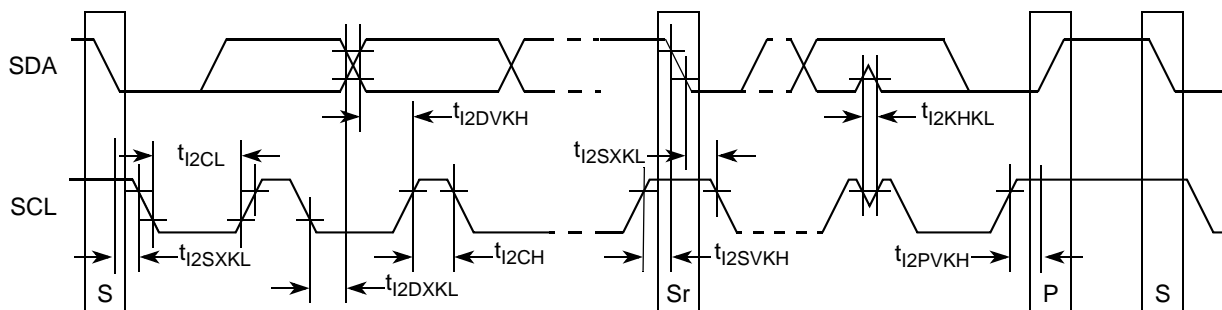

Figure 40. I²C AC Test Load

Figure 41 shows the AC timing diagram for the I²C bus.


Figure 41. I²C Bus AC Timing Diagram

16.5 Receiver Compliance Eye Diagrams

The RX eye diagram in [Figure 56](#) is specified using the passive compliance/test measurement load (see [Figure 57](#)) in place of any real PCI Express RX component.

Note: In general, the minimum Receiver eye diagram measured with the compliance/test measurement load (see [Figure 57](#)) is larger than the minimum Receiver eye diagram measured over a range of systems at the input Receiver of any real PCI Express component. The degraded eye diagram at the input Receiver is due to traces internal to the package as well as silicon parasitic characteristics which cause the real PCI Express component to vary in impedance from the compliance/test measurement load. The input Receiver eye diagram is implementation specific and is not specified. RX component designer should provide additional margin to adequately compensate for the degraded minimum Receiver eye diagram (shown in [Figure 56](#)) expected at the input Receiver based on some adequate combination of system simulations and the Return Loss measured looking into the RX package and silicon. The RX eye diagram must be aligned in time using the jitter median to locate the center of the eye diagram.

The eye diagram must be valid for any 250 consecutive UIs.

A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The eye diagram is created using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI.

NOTE

The reference impedance for return loss measurements is 50. to ground for both the D+ and D- line (that is, as measured by a Vector Network Analyzer with 50. probes—see [Figure 57](#)). Note that the series capacitors, CTX, are optional for the return loss measurement.

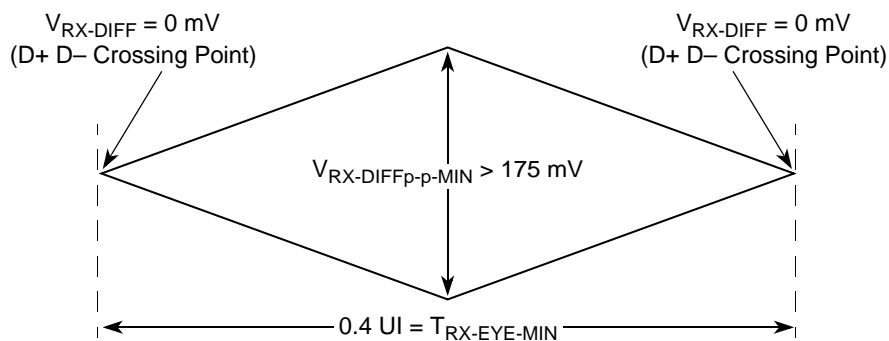


Figure 56. Minimum Receiver Eye Timing and Voltage Compliance Specification

Table 72. Receiver AC Timing Specifications—1.25 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Differential Input Voltage	V_{IN}	200	1600	mV p-p	Measured at receiver
Deterministic Jitter Tolerance	J_D	0.37	—	UI p-p	Measured at receiver
Combined Deterministic and Random Jitter Tolerance	J_{DR}	0.55	—	UI p-p	Measured at receiver
Total Jitter Tolerance ¹	J_T	0.65	—	UI p-p	Measured at receiver
Multiple Input Skew	S_{MI}	—	24	ns	Skew at the receiver input between lanes of a multilane link
Bit Error Rate	BER	—	10^{-12}	—	—
Unit Interval	UI	800	800	ps	+/- 100 ppm

Note:

1. Total jitter is composed of three components, deterministic jitter, random jitter and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of [Figure 59](#). The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk and other variable system effects.

Table 73. Receiver AC Timing Specifications—2.5 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Differential Input Voltage	V_{IN}	200	1600	mV p-p	Measured at receiver
Deterministic Jitter Tolerance	J_D	0.37	—	UI p-p	Measured at receiver
Combined Deterministic and Random Jitter Tolerance	J_{DR}	0.55	—	UI p-p	Measured at receiver
Total Jitter Tolerance ¹	J_T	0.65	—	UI p-p	Measured at receiver
Multiple Input Skew	S_{MI}	—	24	ns	Skew at the receiver input between lanes of a multilane link
Bit Error Rate	BER	—	10^{-12}	—	—
Unit Interval	UI	400	400	ps	+/- 100 ppm

Note:

1. Total jitter is composed of three components, deterministic jitter, random jitter and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of [Figure 59](#). The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk and other variable system effects.

Table 76. MPC8572E Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
TSEC1_RX_DV/FIFO1_RX_D V/FIFO1_RXC[0]	Receive Data Valid	AL24	I	LV _{DD}	1
TSEC1_RX_ER/FIFO1_RX_ER/FIFO1_RXC[1]	Receive Data Error	AM29	I	LV _{DD}	1
TSEC1_TX_CLK/FIFO1_TX_CLK	Transmit Clock In	AB20	I	LV _{DD}	1
TSEC1_TX_EN/FIFO1_TX_EN/FIFO1_TXC[0]	Transmit Enable	AJ24	O	LV _{DD}	1, 22
TSEC1_TX_ER/FIFO1_TX_ER/FIFO1_TXC[1]	Transmit Error	AK25	O	LV _{DD}	1, 5, 9
Three-Speed Ethernet Controller 2					
TSEC2_RXD[7:0]/FIFO2_RXD[7:0]/FIFO1_RXD[15:8]	Receive Data	AG22, AH20, AL22, AG20, AK21, AK22, AJ21, AK20	I	LV _{DD}	1
TSEC2_TXD[7:0]/FIFO2_TXD[7:0]/FIFO1_TXD[15:8]	Transmit Data	AH21, AF20, AC17, AF21, AD18, AF22, AE20, AB18	O	LV _{DD}	1, 5, 9, 24
TSEC2_COL/FIFO2_TX_FC	Collision Detect/Flow Control	AE19	I	LV _{DD}	1
TSEC2_CRS/FIFO2_RX_FC	Carrier Sense/Flow Control	AJ20	I/O	LV _{DD}	1, 16
TSEC2_GTX_CLK	Transmit Clock Out	AE18	O	LV _{DD}	—
TSEC2_RX_CLK/FIFO2_RX_CLK	Receive Clock	AL23	I	LV _{DD}	1
TSEC2_RX_DV/FIFO2_RX_D V/FIFO1_RXC[2]	Receive Data Valid	AJ22	I	LV _{DD}	1
TSEC2_RX_ER/FIFO2_RX_ER	Receive Data Error	AD19	I	LV _{DD}	1
TSEC2_TX_CLK/FIFO2_TX_CLK	Transmit Clock In	AC19	I	LV _{DD}	1
TSEC2_TX_EN/FIFO2_TX_EN/FIFO1_TXC[2]	Transmit Enable	AB19	O	LV _{DD}	1, 22
TSEC2_TX_ER/FIFO2_TX_ER	Transmit Error	AB17	O	LV _{DD}	1, 5, 9
Three-Speed Ethernet Controller 3					
TSEC3_TXD[3:0]/FEC_TXD[3:0]/FIFO3_TXD[3:0]	Transmit Data	AG18, AG17, AH17, AH19	O	TV _{DD}	1, 5, 9
TSEC3_RXD[3:0]/FEC_RXD[3:0]/FIFO3_RXD[3:0]	Receive Data	AG16, AK19, AD16, AJ19	I	TV _{DD}	1

Table 76. MPC8572E Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
Power and Ground Signals					
GND	Ground	A18, A25, A29, C3, C6, C9, C12, C15, C20, C22, E5, E8, E11, E14, F3, G7, G10, G13, G16, H5, H21, J3, J9, J12, J18, K7, L5, L13, L15, L16, L21, M3, M9, M12, M14, M16, M18, N7, N13, N15, N17, N19, N21, N23, P5, P12, P14, P16, P20, P22, R3, R9, R11, R13, R15, R17, R19, R21, R23, R26, T7, T12, T14, T16, T18, T20, T22, T30, U5, U11, U13, U15, U16, U17, U19, U21, U23, U25, V3, V9, V12, V14, V16, V18, V20, V22, W7, W11, W13, W15, W17, W19, W21, W27, W32, Y5, Y12, Y14, Y16, Y18, Y20, AA3, AA9, AA13, AA15, AA17, AA19, AA21, AA30, AB7, AB26, AC5, AC11, AC13, AD3, AD9, AD14, AD17, AD22, AE7, AE13, AF5, AF11, AG3, AG9, AG15, AG19, AH7, AH13, AH22, AJ5, AJ11, AJ17, AK3, AK9, AK15, AK24, AL7, AL13, AL19, AL26	—	—	—
XGND_SRDS1	SerDes Transceiver Pad GND (xpadvss)	C23, C27, D23, D25, E23, E26, F23, F24, G23, G27, H23, H25, J23, J26, K23, K24, L27, M25	—	—	—
XGND_SRDS2	SerDes Transceiver Pad GND (xpadvss)	AD23, AD25, AE23, AE27, AF23, AF24, AG23, AG26, AH23, AH25, AJ27	—	—	—

19 Clocking

This section describes the PLL configuration of the MPC8572E. Note that the platform clock is identical to the core complex bus (CCB) clock.

19.1 Clock Ranges

Table 77 provides the clocking specifications for both processor cores.

Table 77. MPC8572E Processor Core Clocking Specifications

Characteristic	Maximum Processor Core Frequency								Unit	Notes
	1067 MHz		1200 MHz		1333 MHz		1500 MHz			
	Min	Max	Min	Max	Min	Max	Min	Max		
e500 core processor frequency	800	1067	800	1200	800	1333	800	1500	MHz	1, 2
CCB frequency	400	533	400	533	400	533	400	600	MHz	
DDR Data Rate	400	667	400	667	400	667	400	800	MHz	

Notes:

- Caution:** The CCB to SYSCLK ratio and e500 core to CCB ratio settings must be chosen such that the resulting SYSCLK frequency, e500 (core) frequency, and CCB frequency do not exceed their respective maximum or minimum operating frequencies. Refer to [Section 19.2, “CCB/SYSCLK PLL Ratio,”](#) [Section 19.3, “e500 Core PLL Ratio,”](#) and [Section 19.4, “DDR/DDRCLK PLL Ratio,”](#) for ratio settings.
- The processor core frequency speed bins listed also reflect the maximum platform (CCB) and DDR data rate frequency supported by production test. Running CCB and/or DDR data rate higher than the limit shown above, although logically possible via valid clock ratio setting in some condition, is not supported.

The DDR memory controller can run in either synchronous or asynchronous mode. When running in synchronous mode, the memory bus is clocked relative to the platform clock frequency. When running in asynchronous mode, the memory bus is clocked with its own dedicated PLL with clock provided on DDRCLK input pin. [Table 78](#) provides the clocking specifications for the memory bus.

Table 78. Memory Bus Clocking Specifications

Characteristic	Min	Max	Unit	Notes
Memory bus clock frequency	200	400	MHz	1, 2, 3, 4

Notes:

- Caution:** The CCB clock to SYSCLK ratio and e500 core to CCB clock ratio settings must be chosen such that the resulting SYSCLK frequency, e500 (core) frequency, and CCB frequency do not exceed their respective maximum or minimum operating frequencies. Refer to [Section 19.2, "CCB/SYSCLK PLL Ratio,"](#) [Section 19.3, "e500 Core PLL Ratio,"](#) and [Section 19.4, "DDR/DDRCLK PLL Ratio,"](#) for ratio settings.
- The Memory bus clock refers to the MPC8572E memory controllers' Dn_MCK[0:5] and $\overline{\text{Dn_MCK}}[0:5]$ output clocks, running at half of the DDR data rate.
- In synchronous mode, the memory bus clock speed is half the platform clock frequency. In other words, the DDR data rate is the same as the platform (CCB) frequency. If the desired DDR data rate is higher than the platform (CCB) frequency, asynchronous mode must be used.
- In asynchronous mode, the memory bus clock speed is dictated by its own PLL. Refer to [Section 19.4, "DDR/DDRCLK PLL Ratio."](#) The memory bus clock speed must be less than or equal to the CCB clock rate which in turn must be less than the DDR data rate.

As a general guideline when selecting the DDR data rate or platform (CCB) frequency, the following procedures can be used:

- Start with the processor core frequency selection;
- After the processor core frequency is determined, select the platform (CCB) frequency from the limited options listed in [Table 80](#) and [Table 81](#);
- Check the CCB to SYSCLK ratio to verify a valid ratio can be choose from [Table 79](#);
- If the desired DDR data rate can be same as the CCB frequency, use the synchronous DDR mode; Otherwise, if a higher DDR data rate is desired, use asynchronous mode by selecting a valid DDR data rate to DDRCLK ratio from [Table 82](#). Note that in asynchronous mode, the DDR data rate must be greater than the platform (CCB) frequency. In other words, running DDR data rate lower than the platform (CCB) frequency in asynchronous mode is not supported by MPC8572E.
- Verify all clock ratios to ensure that there is no violation to any clock and/or ratio specification.

19.2 CCB/SYSCLK PLL Ratio

The CCB clock is the clock that drives the e500 core complex bus (CCB), and is also called the platform clock. The frequency of the CCB is set using the following reset signals, as shown in [Table 79](#):

- SYSCLK input signal
- Binary value on LA[29:31] at power up

Note that there is no default for this PLL ratio; these signals must be pulled to the desired values. Also note that, in synchronous mode, the DDR data rate is the determining factor in selecting the CCB bus frequency, because the CCB frequency must equal the DDR data rate. In asynchronous mode, the memory bus clock frequency is decoupled from the CCB bus frequency.

logic does not interfere with normal chip operation. While the TAP controller can be forced to the reset state using only the TCK and TMS signals, generally systems assert $\overline{\text{TRST}}$ during the power-on reset flow. Simply tying $\overline{\text{TRST}}$ to $\overline{\text{HRESET}}$ is not practical because the JTAG interface is also used for accessing the common on-chip processor (COP), which implements the debug interface to the chip.

The COP function of these processors allow a remote computer system (typically, a PC with dedicated hardware and debugging software) to access and control the internal operations of the processor. The COP interface connects primarily through the JTAG port of the processor, with some additional status monitoring signals. The COP port requires the ability to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$ to fully control the processor. If the target system has independent reset sources, such as voltage monitors, watchdog timers, power supply failures, or push-button switches, then the COP reset signals must be merged into these signals with logic.

The arrangement shown in [Figure 66](#) allows the COP port to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$, while ensuring that the target can drive $\overline{\text{HRESET}}$ as well.

The COP interface has a standard header, shown in [Figure 65](#), for connection to the target system, and is based on the 0.025" square-post, 0.100" centered header assembly (often called a Berg header). The connector typically has pin 14 removed as a connector key.

The COP header adds many benefits such as breakpoints, watchpoints, register and memory examination/modification, and other standard debugger features. An inexpensive option can be to leave the COP header unpopulated until needed.

There is no standardized way to number the COP header; so emulator vendors have issued many different pin numbering schemes. Some COP headers are numbered top-to-bottom then left-to-right, while others use left-to-right then top-to-bottom. Still others number the pins counter-clockwise from pin 1 (as with an IC). Regardless of the numbering scheme, the signal placement recommended in [Figure 65](#) is common to all known emulators.

21.9.1 Termination of Unused Signals

If the JTAG interface and COP header is not used, Freescale recommends the following connections:

- $\overline{\text{TRST}}$ should be tied to $\overline{\text{HRESET}}$ through a 0 k Ω isolation resistor so that it is asserted when the system reset signal ($\overline{\text{HRESET}}$) is asserted, ensuring that the JTAG scan chain is initialized during the power-on reset flow. Freescale recommends that the COP header be designed into the system as shown in [Figure 66](#). If this is not possible, the isolation resistor allows future access to $\overline{\text{TRST}}$ in case a JTAG interface may need to be wired onto the system in future debug situations.
- No pull-up/pull-down is required for TDI, TMS, TDO or TCK.